

Notice of References Cited	Application/Control No. 09/806,417	Applicant(s)/Patent Under Reexamination SEKIDO ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6159414 ✓	12-2000	Tunis, III et al.	264/510
	C	US-5169590 ✓	12-1992	Johnson et al.	264/506
	D	US-5985197 ✓	11-1999	Nelson et al.	264/221
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	H	US-5939013 ✓	08-1999	Han et al.	264/510
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	N	WO 98/32589	07-1998	WIPO	Lunde et al.	
	O	WO 98/30374	07-1998	WIPO	Lopez et al	
	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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